

# Search Notes



Application/Control No.

10/613,332

Examiner

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Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

3767

## SEARCHED

Class	Subclass	Date	Examiner
604	96.01	3/16/2006	mlh
	103.06		
	103.07		
	103.08		
	103.09		
	103.11		
428	36.9		
525	166		
	179		
606	192		
	193		
	194		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
as	above	3/16/2006	mlh
interference search history printout		3/16/2006	mlh

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST text search	3/16/06	mlh
Inventor name search	7/11/2005	mlh